Applicant(s)/Patent Under Reexamination 10/024,857 WALLACH ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2175 Thuy Pardo

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2004/0082000	04-2004	Stanton, Vincent P. JR.	435/006
	В	US-2004/0006553	01-2004	de Vries et al.	707/1
	С	US-2003/0208378	11-2003	Thangaraj et al.	705/2
	D	US-2003/0097220	05-2003	Agur et al.	702/19
	Е	US-2003/0097077	05-2003	Morganroth, Joel	600/509
	F	US-2002/0095258	07-2002	Agur et al.	702/19
	G	US-2002/0012921	01-2002	Stanton, Vincent P. JR.	435/6
	Н	US-6,317,731	11-2001	Luciano, Joanne Sylvia	706/21
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U					
	V					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.